

**Search Notes****Application/Control No.**

10/565,394

**Examiner**

Hau V. Phan

**Applicant(s)/Patent under  
Reexamination**

KOBAYASHI ET AL.

**Art Unit**

3618

**SEARCHED**

Class	Subclass	Date	Examiner
180	89.2 309	2/19/2008	HP
	296		
	219		
181	250	2/19/2008	HP
	207		
	273		
	227		
60	322	2/19/2008	HP
	299		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR